



Micro Commercial Components

Reliability Report

Part Number: Transistors THT Series

Yearly Reliability monitoring:2023
Based on similar Structural

Test Results : **PASS**

Test Item	Conditions	Duration	Quantity	Rejects
TEST Pre- and Post-Stress Electrical Test	$T_a = 25\text{ }^\circ\text{C}$	N/A	all parts	see below
HTRB High Temperature Reverse Bias	MIL-STD-750 Method 1038 $T_j = T_{jmax}$, 80% VCBO	1000 hours	77Pcs	0
TC Temperature Cycling	JESD22-A104 -55 $^\circ\text{C}$ (+0,-10)/15Min~ 150(+15,-0)/15Min,	1000Cycles (500hours)	77Pcs	0
AC Autoclave	JESD22-A102 $T_a = 121\text{ }^\circ\text{C} \pm 2\text{ }^\circ\text{C}$, RH = 100 %, 15psig	96 hours	77Pcs	0
H3TRB High Humidity High Temperature Reverse Bias	JESD22-A101 $T_a = 85\text{ }^\circ\text{C} \pm 2\text{ }^\circ\text{C}$, RH = 85% \pm 5%, 80 % VCBO (VCBO MAX=100V)	1000 hours	77Pcs	0
IOL Intermittent Operating Life	MIL-STD-750 Method 1037 ON 2Min/OFF 2min, devices powered to insure $\Delta T_j \geq 100\text{ }^\circ\text{C}$	15000 cycles (1000 hours)	77Pcs	0
RSH Resistance to Solder Heat	JESD22-B106 260 $^\circ\text{C}$ (+5 , -0)	10 s	30Pcs	0
SD Solderability	J-STD-002 235 $^\circ\text{C} \pm 5\text{ }^\circ\text{C}$	3 s	10Pcs	0
HTSL High Temperature Storage Life	JESD22-A103 T_{stgMax}	1000 hours	77Pcs	0